

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/578,635	AISO, SEIJI	
Examiner		Art Unit		Page 1 of 1
AARON W. CARTER		2624		

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0051072	05-2002	Sumitomo et al.	348/362
*	B	US-2001/0010546	08-2001	CHEN, SHENCHANG ERIC	348/218
*	C	US-7,495,709	02-2009	Abe, Koichi	348/586
*	D	US-2005/0013466	01-2005	Beun, Robbie Daniel Pieter	382/107
*	E	US-7,376,249	05-2008	Beun, Robbie Daniel Pieter	382/107
*	F	US-2005/0175235	08-2005	Luo et al.	382/159
*	G	US-2005/0063598	03-2005	Sen et al.	382/232
*	H	US-5,999,662	12-1999	Burt et al.	382/284
*	I	US-6,834,128	12-2004	Altunbasak et al.	382/284
*	J	US-7,460,730	12-2008	Pal et al.	382/284
*	K	US-2007/0133901	06-2007	Aiso, Seiji	382/294
*	L	US-2004/0225221	11-2004	Olsson, Lars Jonas	600/447
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO98/02844	01-1998	WIPO	PELEG ET AL	G06K 9/00
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.